

<b>Notice of References Cited</b>	Application/Control No. 09/311,952	Applicant(s)/Patent Under Reexamination MURAYAMA ET AL.	
	Examiner Hai V. Nguyen	Art Unit 2142	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,393,459	07-1983	Huntley et al.	711/152
	B	US-4,649,479	03-1987	Advani et al.	709/1
	C	US-4,982,324	01-1991	McConaughy et al.	709/222
	D	US-5,023,774	06-1991	Sakai et al.	710/29
	E	US-5,107,456	04-1992	Schuur, Cornelis C. M.	710/305
	F	US-5,109,515	04-1992	Laggis et al.	707/10
	G	US-5,471,634	11-1995	Giorgio et al.	707/104.1
	H	US-5,564,019	10-1996	Beausoleil et al.	709/215
	I	US-5,668,943	09-1997	Altanasio et al.	714/7
	J	US-5,787,264	07-1998	Christiansen et al.	710/113
	K	US-5,771,354	06-1998	Crawford, Christopher M.	709/229
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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